



US00D663337S

(12) **United States Design Patent**  
**Chan et al.**

(10) **Patent No.:** **US D663,337 S**  
(45) **Date of Patent:** **\*\* Jul. 10, 2012**

(54) **ELECTRON MICROSCOPE**

(75) Inventors: **Yi-Chia Chan**, Kaohsiung (TW);  
**Yu-Jen Chen**, Kaohsiung (TW);  
**Po-Song Li**, Kaohsiung (TW);  
**Jiun-Ching Ruan**, Kaohsiung (TW)

(73) Assignee: **MicroLinks Technology Corp.**,  
Kaohsiung (TW)

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/392,067**

(22) Filed: **May 17, 2011**

(51) **LOC (9) Cl.** ..... **16-06**

(52) **U.S. Cl.** ..... **D16/131**

(58) **Field of Classification Search** ..... D16/130,  
D16/131; 359/385, 368, 399, 802, 803, 806,  
359/808, 809, 810, 817, 379; 362/202, 205;  
D26/37; D8/107, 83

See application file for complete search history.

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

3,582,181	A *	6/1971	Manau de Chveca	.....	359/379
D275,575	S *	9/1984	Henderson	.....	D16/131
4,729,635	A *	3/1988	Saferstein et al.	.....	359/804
D331,934	S *	12/1992	Tak	.....	D16/131
5,267,087	A *	11/1993	Weidemann	.....	359/801
D349,295	S *	8/1994	Weidemann	.....	D16/131
D361,078	S *	8/1995	Atamian	.....	D16/131
D366,200	S *	1/1996	Di Vittorio	.....	D8/107
5,644,425	A *	7/1997	Palmer	.....	359/409
D418,853	S *	1/2000	Kubota	.....	D16/203

D523,883	S *	6/2006	Distasio et al.	.....	D16/131
D532,026	S *	11/2006	Sosniak et al.	.....	D16/130
D537,459	S *	2/2007	Yip et al.	.....	D16/131
D537,965	S *	3/2007	Lee	.....	D26/37
D539,317	S *	3/2007	Tonhofer	.....	D16/132
7,221,402	B2 *	5/2007	Cheng	.....	348/375
7,336,884	B2 *	2/2008	Zhou et al.	.....	385/134
D564,553	S *	3/2008	Yip et al.	.....	D16/131
D564,554	S *	3/2008	Shih et al.	.....	D16/131
D571,386	S *	6/2008	Lipsiner et al.	.....	D16/131
D637,218	S *	5/2011	Shih et al.	.....	D16/130
D655,325	S *	3/2012	Nojima et al.	.....	D16/131
D655,326	S *	3/2012	Nojima et al.	.....	D16/131

\* cited by examiner

*Primary Examiner* — Paula Greene

(74) *Attorney, Agent, or Firm* — Muncy, Geissler, Olds & Lowe, PLLC

(57) **CLAIM**

The ornamental design for an electron microscope, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of the electron microscope showing our new design;

FIG. 2 is a front elevation view thereof;

FIG. 3 is a rear elevation view thereof;

FIG. 4 is a left side view thereof;

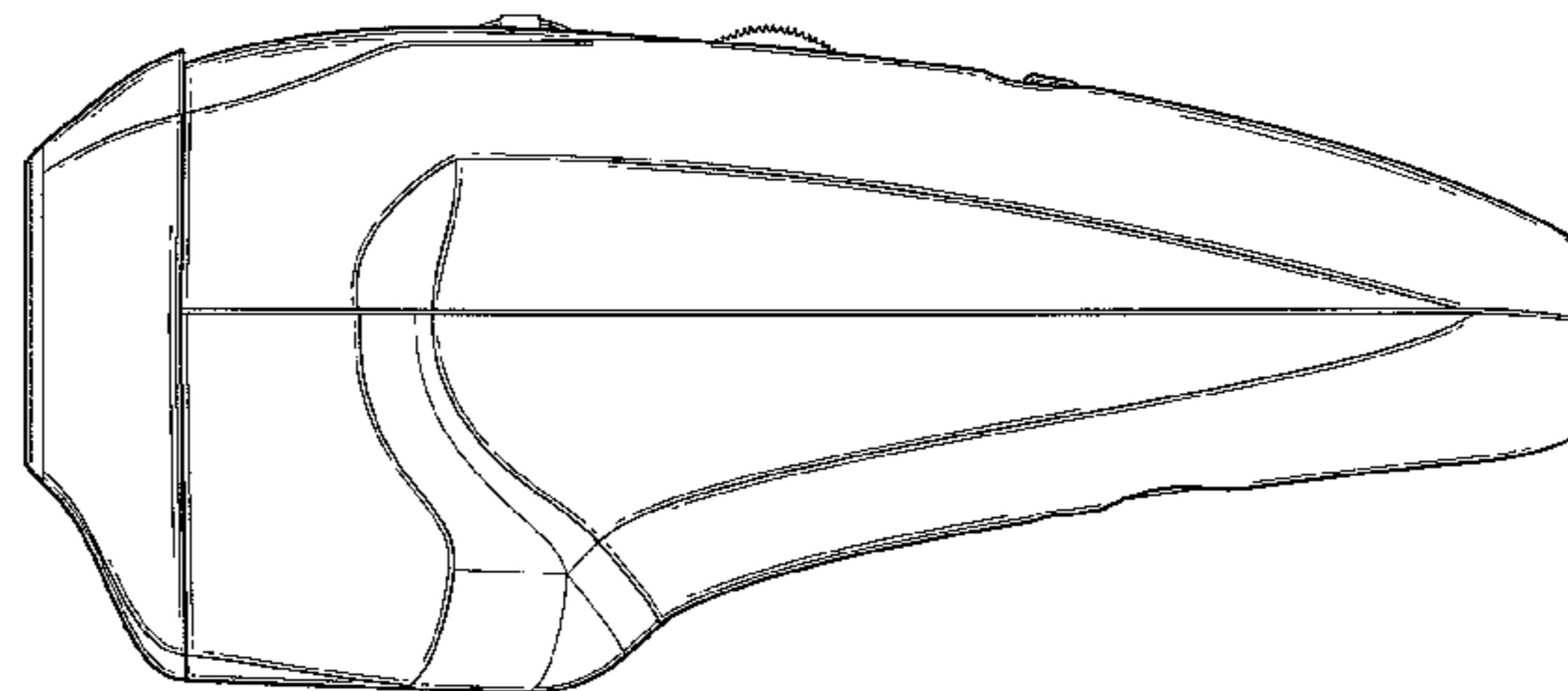
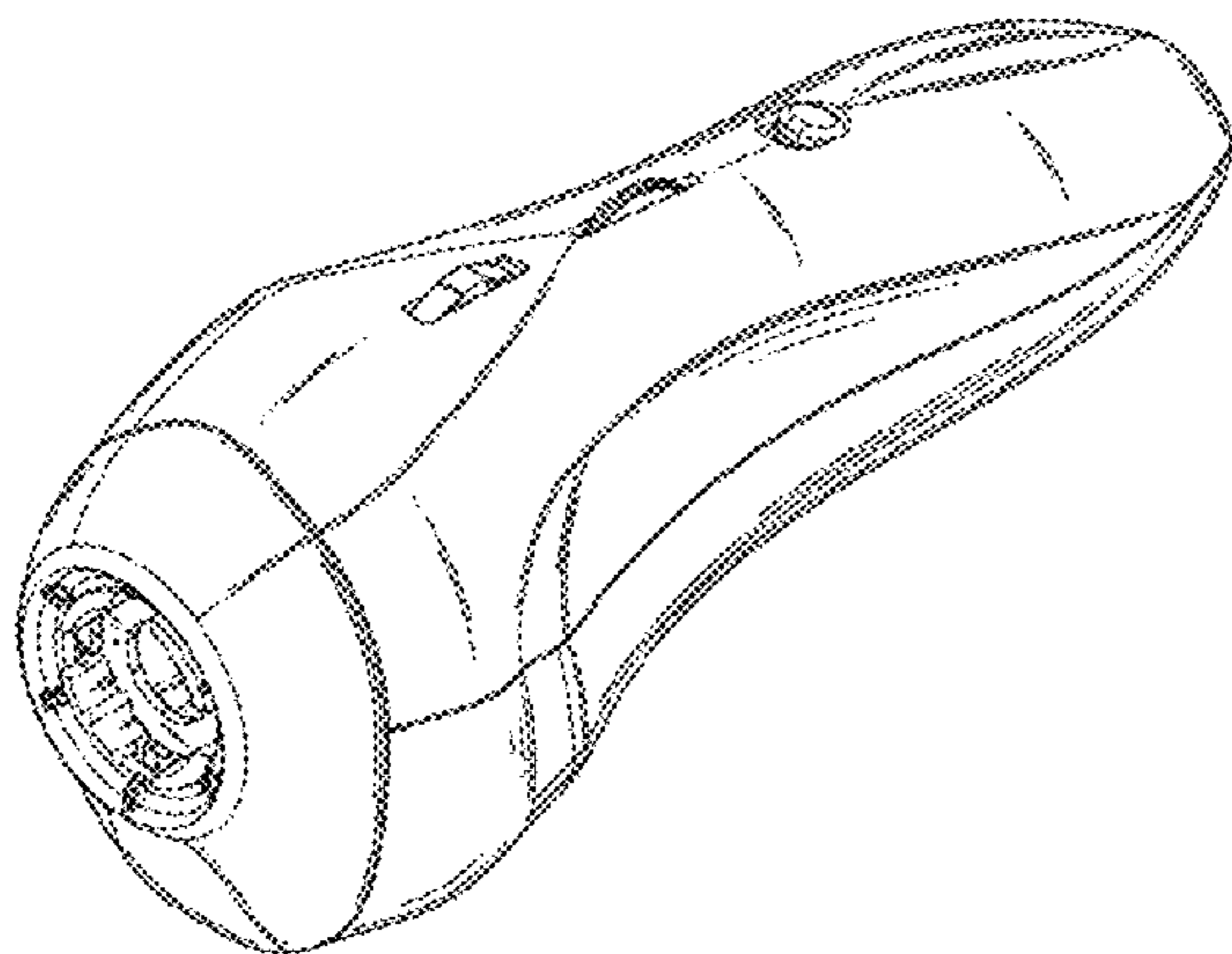
FIG. 5 is a right side view thereof;

FIG. 6 is a top elevation view thereof; and,

FIG. 7 is a bottom perspective view.

The broken lines illustrate portions of the electron microscope that form no part of the claimed design.

**1 Claim, 4 Drawing Sheets**



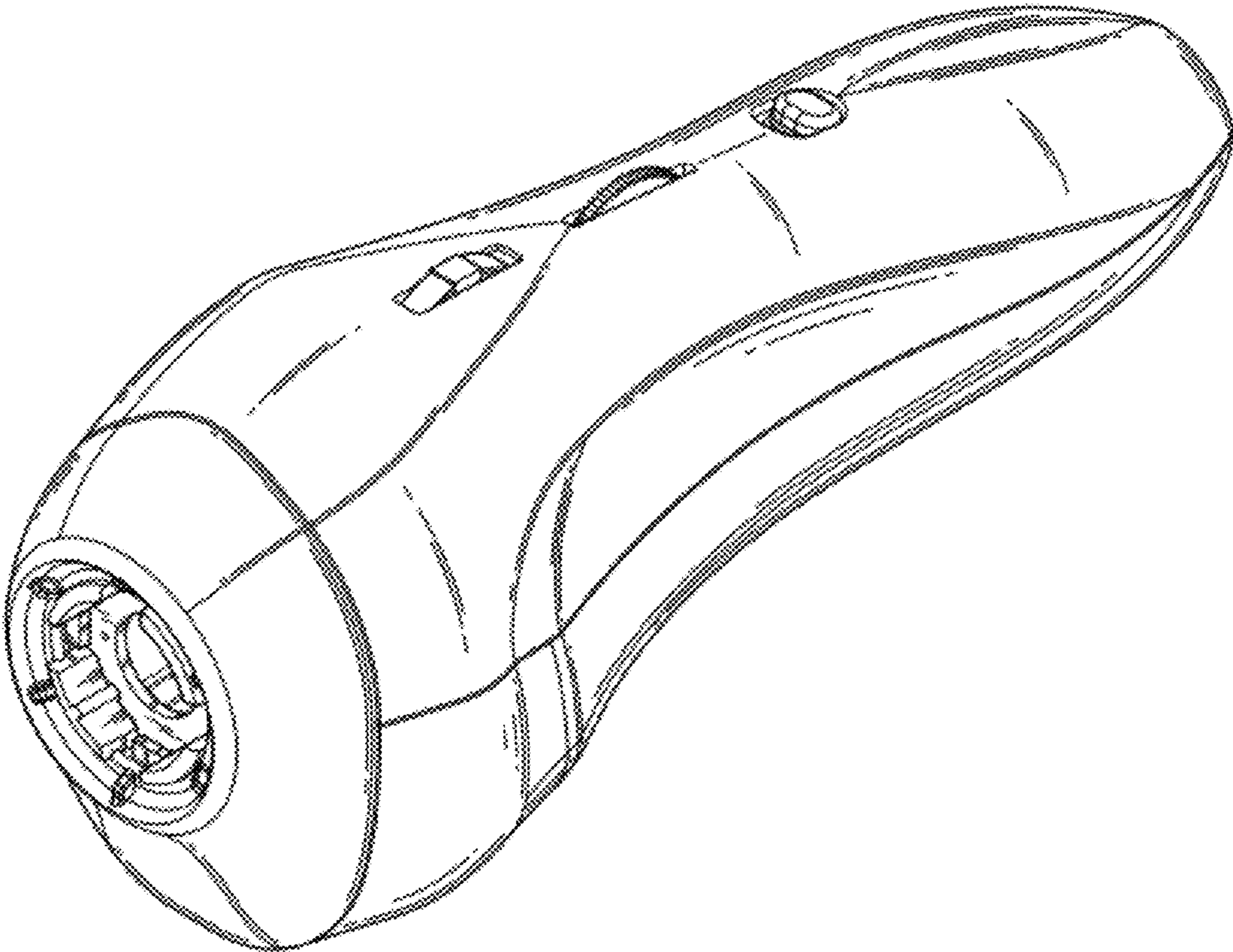


Fig . 1

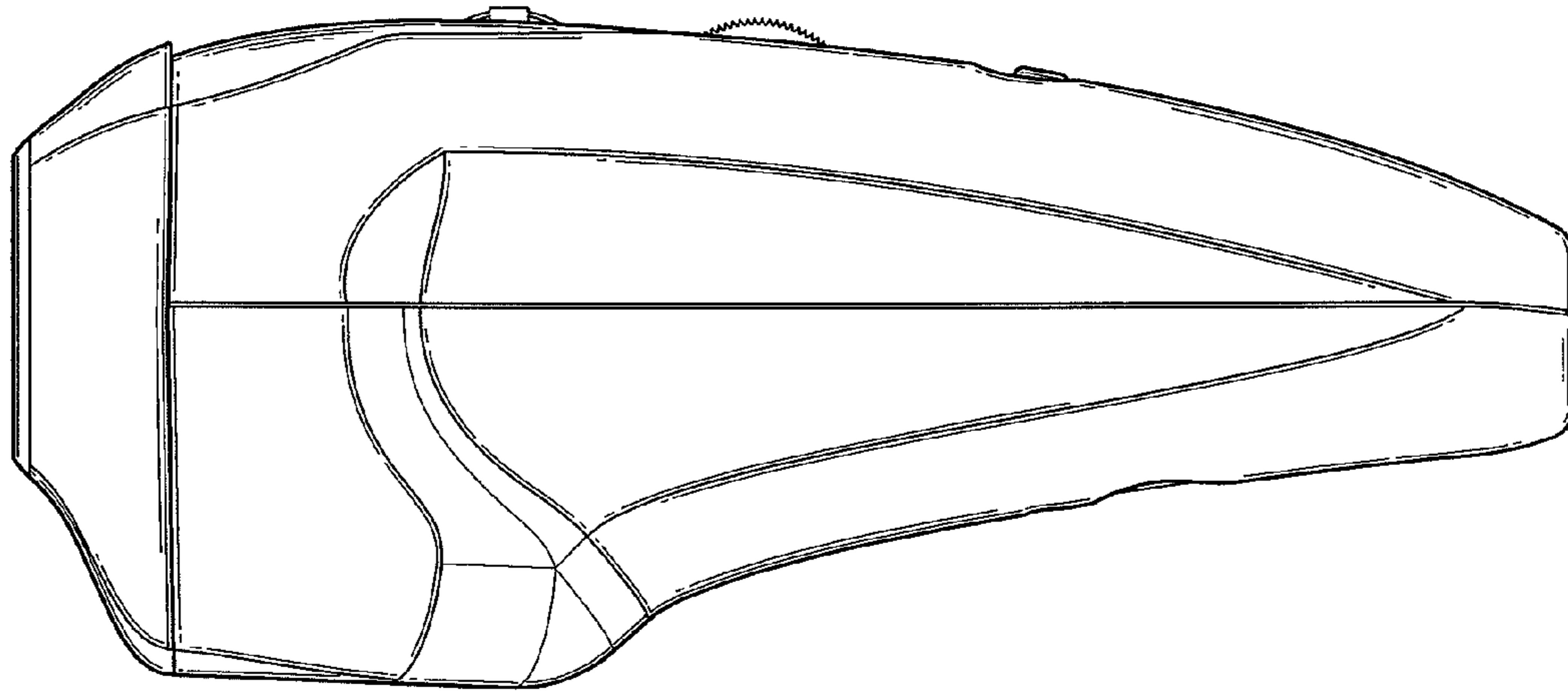


Fig . 2

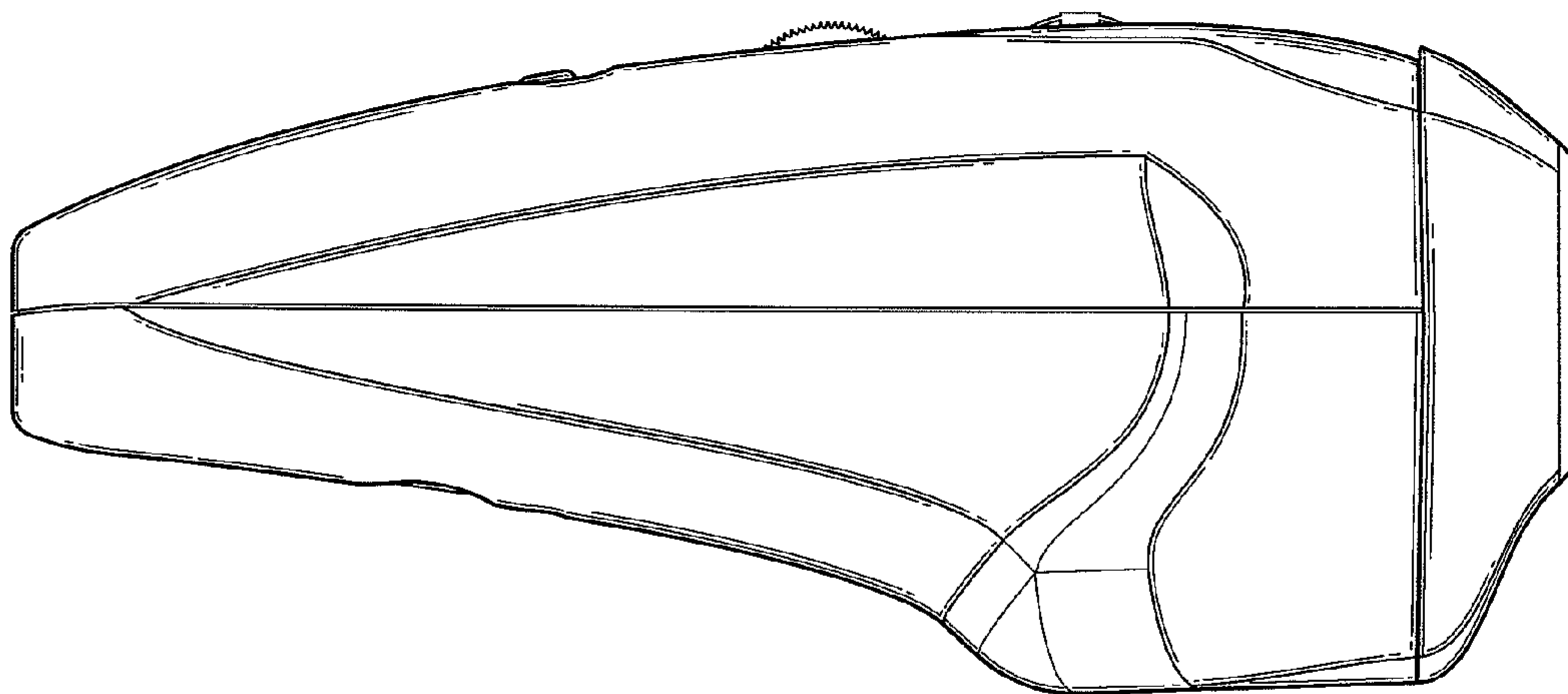


Fig . 3

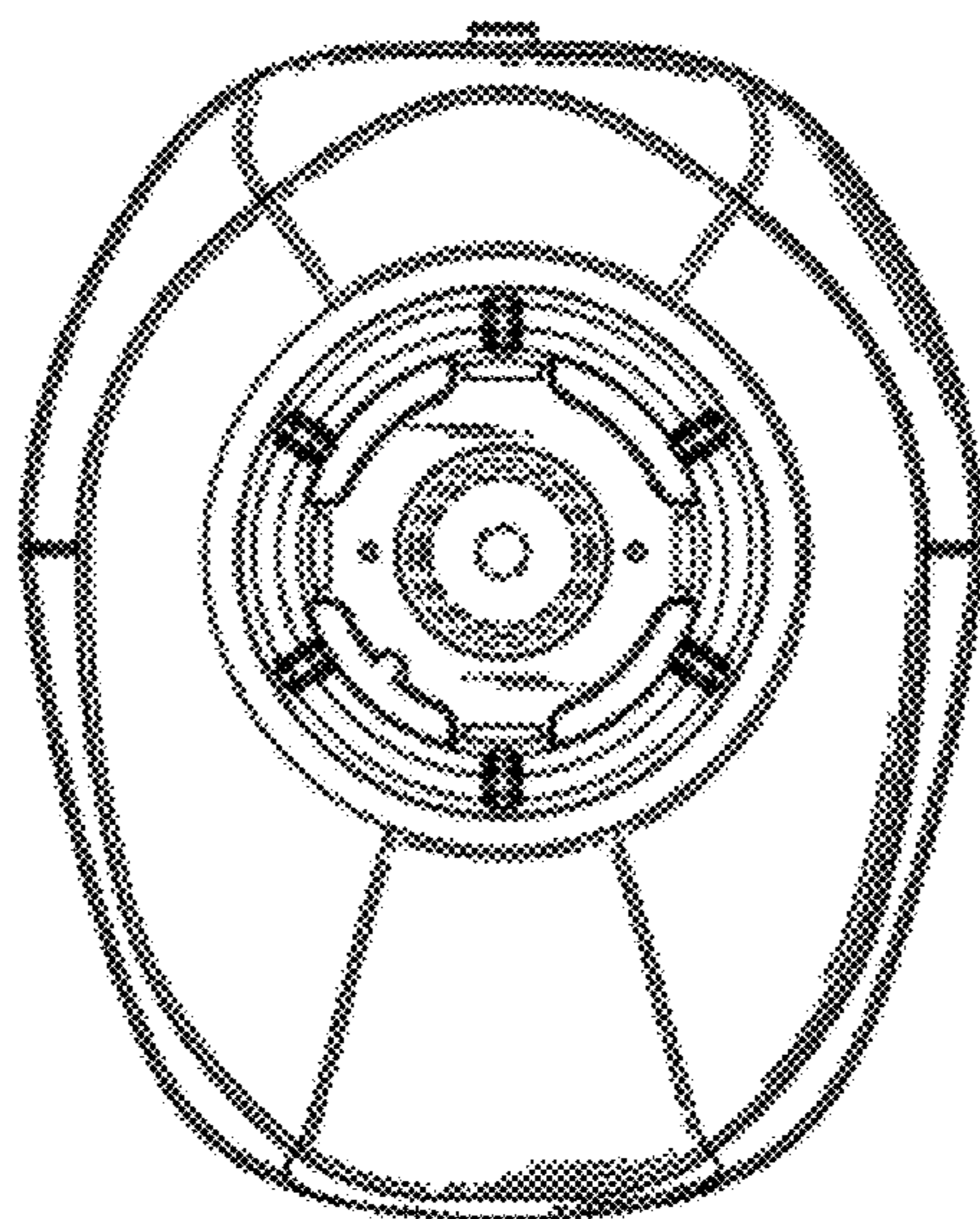


Fig . 4

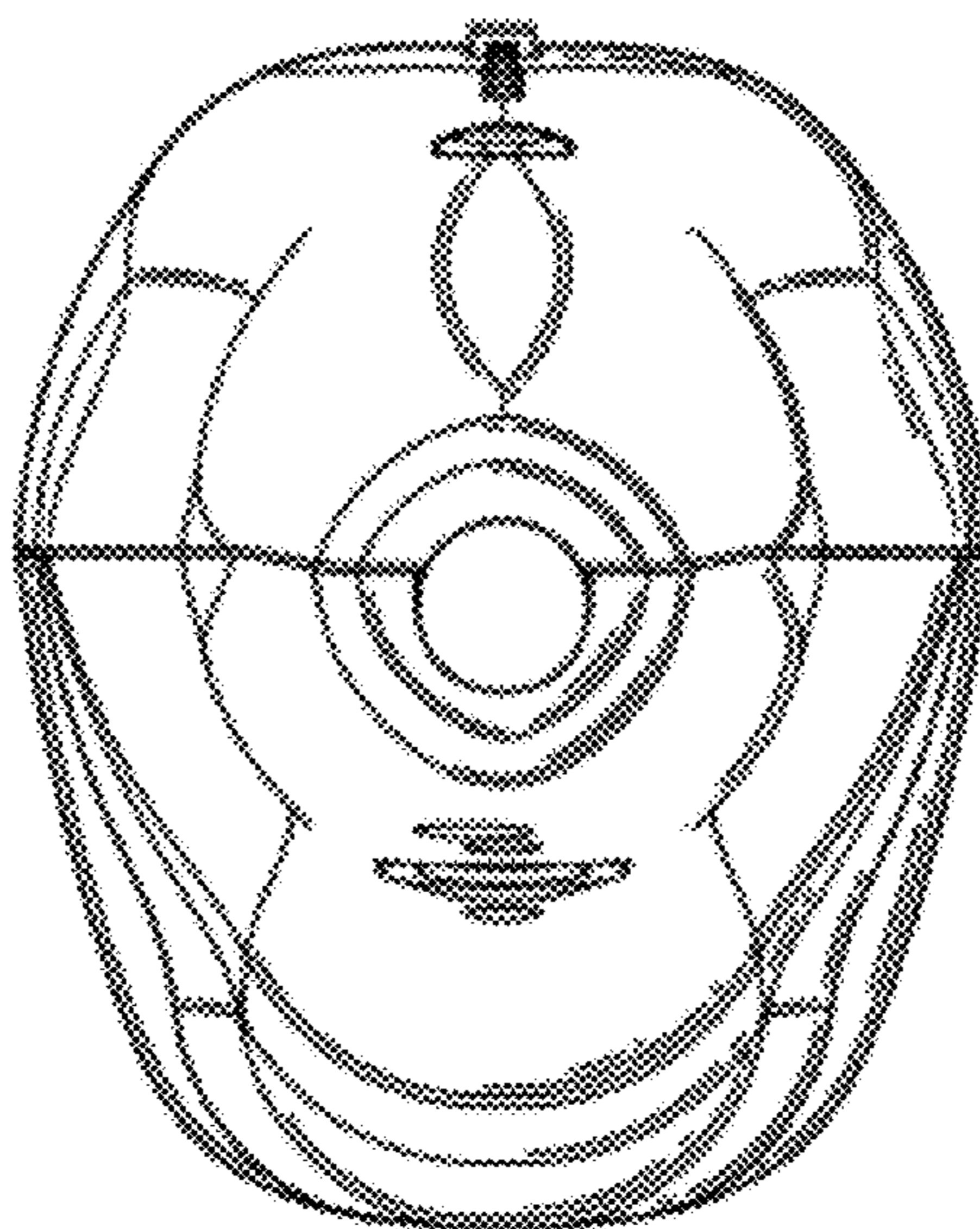


Fig . 5

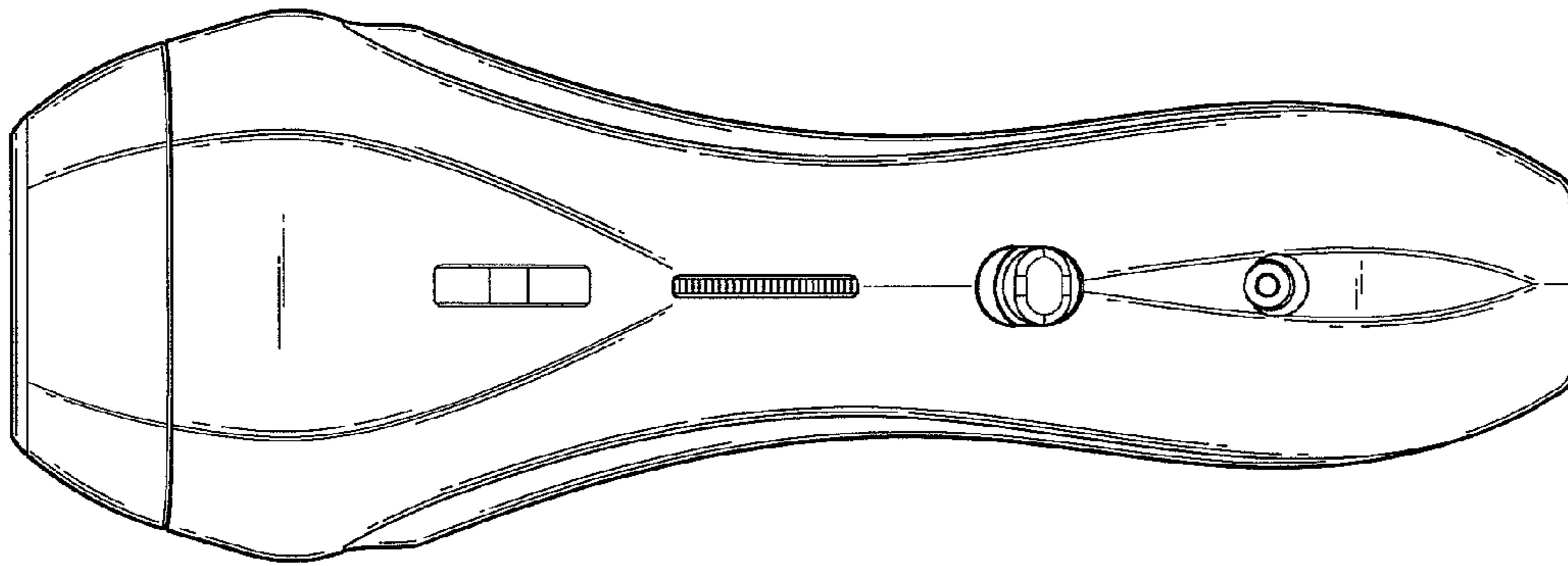


Fig . 6

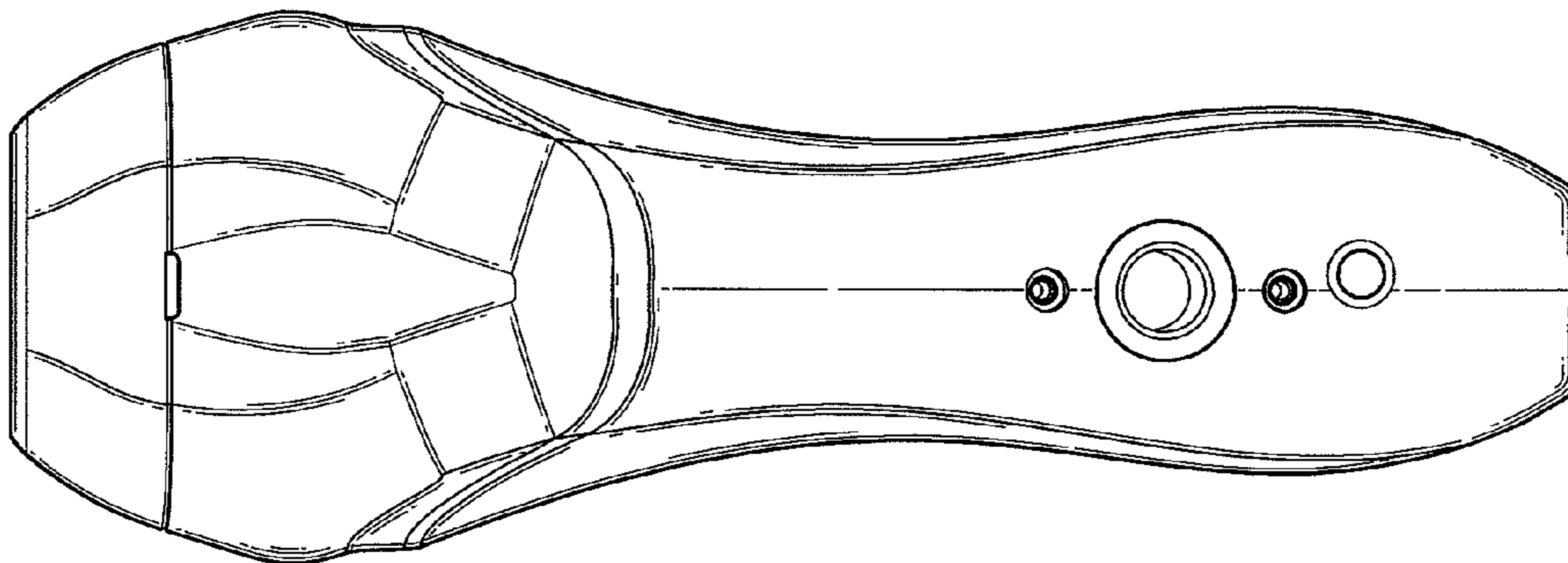


Fig . 7